

Õppekirjandus

1. M.L.Bushnell, V.D.Agrawal. Essentials of Electronic testing. *Kluwer Acad. Publishers*, 2013.
2. L.-T.Wang, C.-W.Wu, X.Wen. VLSI Test Principles and Architectures. Elsevier, 2006, 777 p.
3. **R.Ubar**. Digitaalsüsteemide diagnostika I. Diagnostiline modelleerimine. TTÜ Kirjastus, 148 lk., 2005 (II osa Internetis)
4. **R.Ubar**, A.Jasnetski, A.Tsertov, S.Oyeniran. Software-Based Self-Test With Decision Diagrams for Microprocessors, 174 p., 2018 (Manuscript in Internet)
5. **R.Ubar**, J.Raik, T.Vierhaus „Design and Test Technology for Dependable Systems-on-Chip “. IGI Global, USA, 2011
6. O.Novak, E.Gramatova, **R.Ubar**. Handbook of Testing Electronic Systems. Czech TU Publishing House, 2005, 395 p.

Õppekirjandus (2)

1. A.Miczo. Digital Logic Testing and Simulation. Wiley-Interscience, New Jersey, 2003, 668 p.
2. N.Jha, S.Gupta. Testing of Digital Systems. Cambridge Univ. Press, 2003, 1000 p.
3. H.-J.Wunderlich, Ed. Models in Hardware Testing. Springer, 2010
4. R.Drechsler, S.Eggersglüss, G.Fey, D.Tille. Test Pattern Generation using Boolean Proof Engines. Springer, 2009, 192 p.
5. D.K. Pradhan, I.G.Harris, Eds. Practical Design Verification. Cambridge Univ. Press, 2009, 276 p.
6. D.Gizopoulos. Advances in Electronic Testing, Technology & Engineering. Springer, 2006.
7. D.Gizopoulos, A.Paschalis, Y.Zorian. Embedded Processor-Based Self-Test. Kluwer Acad. Publishers, 2004, 216 p.